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Application/Control No.
10/784,617
Examiner
HOANIC NOUVEN

	Applicant(s)/Pate Reexamination	nt under
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Class	Subclass	Date	Examiner
349	96	3/14/2007	CHN
349	112	3/14/2007	CHN
349	159	3/14/2007	CHN
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	es above and search	3/14/2007	CHN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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East search in US-PGPUB, USPAT, EPO, JPO, Derwent and IBM_TDB	9/14/2007	CHN
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